



**PATENT**

**THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Application No.: 10/791,629  
Filing Date: March 3, 2004  
Applicant: Soo-Chan LEE et al.  
Group Art Unit: 2829  
Examiner: Jermele M. Hollington  
Title: SYSTEM AND METHOD FOR TESTING SEMICONDUCTOR DEVICES  
Attorney Docket: 2421-000033/US

Customer Service Window  
Randolph Building  
401 Dulany Street  
Alexandria, VA 22314  
**Mail Stop RCE**

April 27, 2007

**REQUEST FOR CONTINUED EXAMINATION  
AND AMENDMENT UNDER 37 C.F.R. § 1.114**

Sir:

In response to the Final Office Action mailed December 27, 2006, the due date having been extended one (1) month, the following amendments and remarks are respectfully submitted in connection with the above-identified application.

**Listing of the Claims** begin on page 2 of this Amendment.

**Remarks** begin on page 16 of this Amendment.

	Claims remaining after Amendment		Highest number previously paid for		Present extra
<b>Total</b>	40	-	42	=	0
<b>Independent</b>	13	-	13	=	0

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